

Notice of References Cited	Application/Control No. 10/540,086		Applicant(s)/Patent Under Reexamination HANUMANTHAPPA ET AL.	
	Examiner Sarae Bausch PhD		Art Unit 1634	Page 1 of 2

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,541,308	07-1996	Hogan et al.	536/23.1
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	D	US-			
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	J	US-			
	K	US-			
	L	US-			
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Kamerbeek et al. (J Clin Microbiol, 1997, vol 35, pp. 907-914)
	V	Furugen (Microbial Pathogenesis 2001, vol. 30, pp 129-138)
	W	Buck et al (Biotechniques (1999) 27(3):528-536)
	X	Taylor (J. Clin. Microbiol. 1997, vol. 35, pp. 79-85)

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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